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**Surface chemical analysis — Auger  
electron spectroscopy — Description  
of selected instrumental performance  
parameters**

*Analyse chimique des surfaces — Spectroscopie d'électrons Auger  
— Description de certains paramètres relatifs à la performance  
instrumentale*

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## Foreword

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The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see [www.iso.org/directives](http://www.iso.org/directives)).

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The committee responsible for this document is ISO/TC 201, *Surface chemical analysis*, Subcommittee SC 7, *Electron spectroscopies*.

This second edition cancels and replaces the first edition (ISO 15471:2004), of which it constitutes a minor revision with the following modifications:

- addition of a Bibliography;
- minor editorial changes to the text.

## Introduction

Auger electron spectrometers (AESs) and scanning Auger electron microscopes (SAMs) are produced by many manufacturers throughout the world. While the basic principles of the AES analytical method in each instrument are the same, the specific designs of the instruments and the way that performance specifications are provided differ widely. As a result, it is often difficult to compare the performance of instruments from one manufacturer with those from another. This International Standard provides a basic list of items devised to enable all Auger electron spectrometers to be described in a common manner. This International Standard is not intended to replace the manufacturer's specification, which may extend to 30 or more pages. It is intended that, where certain items are contained in that specification, there are agreed and defined meanings to those items.

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